

捷多邦 5428, SN54LS28, SN7428, SN74LS28
QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS

SDLS094 – DECEMBER 1983 – REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

description

These devices contain four independent 2-input NOR buffer gates.

The SN5428, and SN54LS28 are characterized for operation over the full military temperature range of -55°C to 125°C. The SN7428, and SN74LS28 are characterized for operation from 0°C to 70°C.

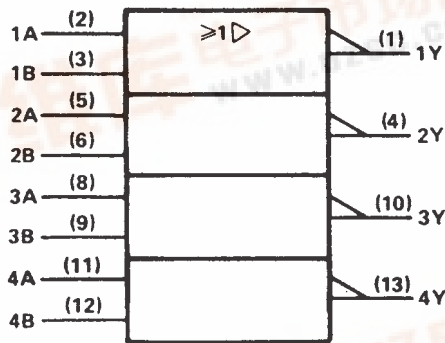
FUNCTION TABLE (each gate)

INPUTS		OUTPUT
A	B	Y
H	X	L
X	H	L
L	L	H

positive logic

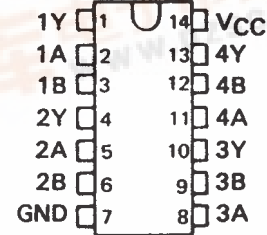
$$Y = \overline{A + B} \text{ or } Y = \overline{A \cdot B}$$

logic symbol†

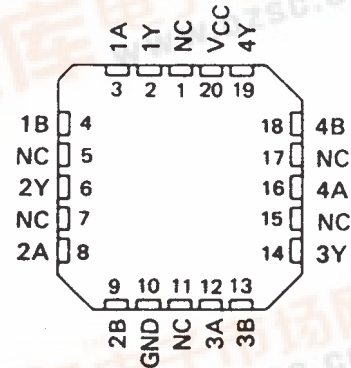


† This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for D, J, N, and W packages.

SN5428, SN54LS28 . . . J OR W PACKAGE
 SN7428 . . . N PACKAGE
 SN74LS28 . . . D OR N PACKAGE
 (TOP VIEW)

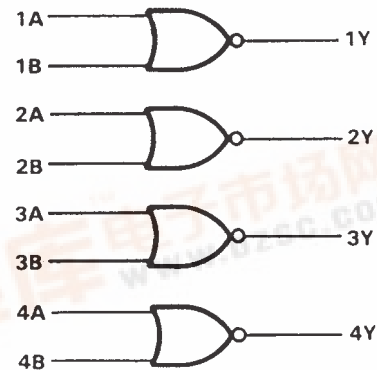


SN54LS28 . . . FK PACKAGE
 (TOP VIEW)



NC - No internal connection

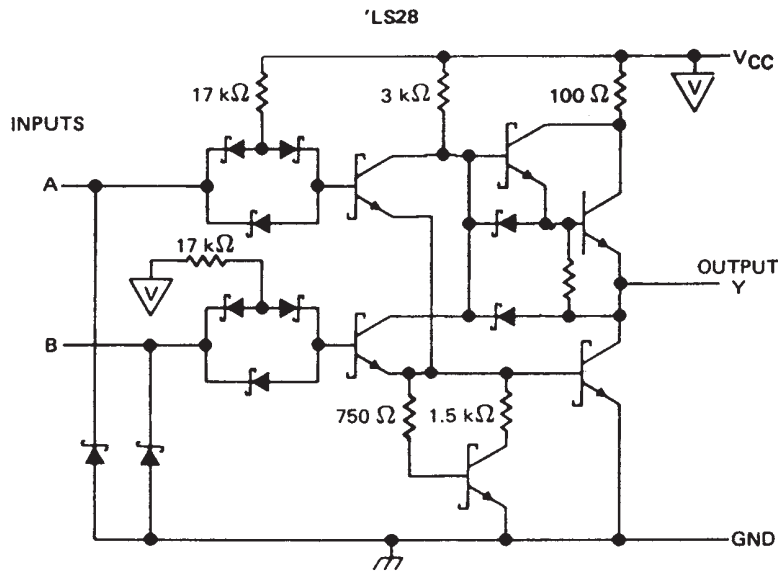
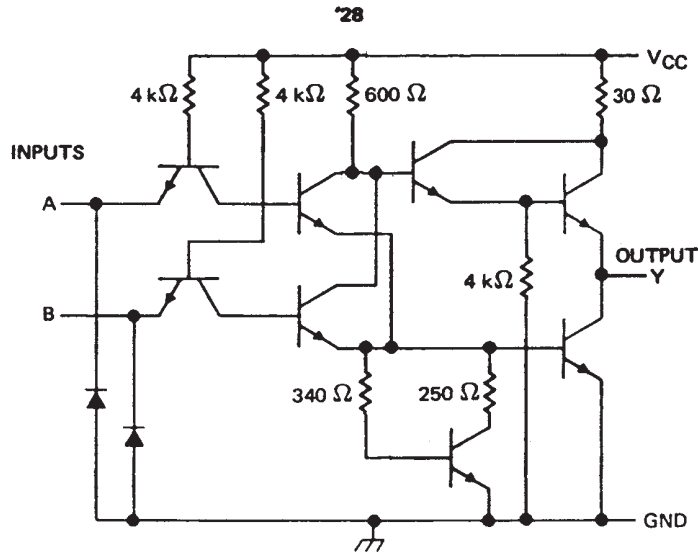
logic diagram



SN5428, SN54LS28, SN7428, SN74LS28 QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS

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schematics (each gate)



Resistor values shown are nominal.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1)	7 V
Input voltage: '28	5.5 V
'LS28	7 V
Operating free-air temperature: SN54'	-55°C to 125°C
SN74'	0°C to 70°C
Storage temperature range	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

SN5428, SN54LS28, SN7428, SN74LS28 QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS

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recommended operating conditions

	SN5428			SN7428			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.8			0.8	V
I _{OH} High-level output current			-2.4			-2.4	mA
I _{OL} Low-level output current			48			48	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	MIN	TYP ‡	MAX	UNIT
V _{IK}	V _{CC} = MIN, I _I = -12mA			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = 0.8 V, I _{OH} = -2.4 mA	2.4	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 48 mA		0.2	0.4	V
I _I	V _{CC} = MAX, V _I = 5.5 V			1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.4 V			40	μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-1.6	mA
I _{OS} §	V _{CC} = MAX	-70		-180	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		12	21	mA
I _{CCL}	V _{CC} = MAX, See Note 2		33	57	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second.

NOTE 2: One input at 4.5 V, all others at GND.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A or B	Y	R _L = 133 Ω, C _L = 50 pF		6	9	ns
t _{PHL}					8	12	ns
t _{PLH}			R _L = 133 Ω, C _L = 150 pF		10	15	ns
t _{PHL}					12	18	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

SN5428, SN54LS28, SN7428, SN74LS28 QUADRUPLE 2-INPUT POSITIVE-NOR BUFFERS

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recommended operating conditions

	SN54LS28			SN74LS28			UNIT
	MIN	NOM	MAX	MIN	NOM	MAX	
V _{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V _{IH} High-level input voltage	2			2			V
V _{IL} Low-level input voltage			0.7			0.8	V
I _{OH} High-level output current			-1.2			-1.2	mA
I _{OL} Low-level output current			12			24	mA
T _A Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS †	SN54LS28			SN74LS28			UNIT
		MIN	TYP ‡	MAX	MIN	TYP ‡	MAX	
V _{IK}	V _{CC} = MIN, I _I = -18 mA			-1.5			-1.5	V
V _{OH}	V _{CC} = MIN, V _{IL} = MAX, I _{OH} = -1.2 mA	2.5	3.4		2.7	3.4		V
V _{OL}	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 12 mA		0.25	0.4		0.24	0.4	V
	V _{CC} = MIN, V _{IH} = 2 V, I _{OL} = 24 mA					0.35	0.5	
I _I	V _{CC} = MAX, V _I = 7 V			0.1			0.1	mA
I _{IH}	V _{CC} = MAX, V _I = 2.7 V			20			20	μA
I _{IL}	V _{CC} = MAX, V _I = 0.4 V			-0.4			-0.4	mA
I _{OS} §	V _{CC} = MAX	-30		-130	-30		-130	mA
I _{CCH}	V _{CC} = MAX, V _I = 0 V		1.8	3.6		1.8	3.6	mA
I _{CCL}	V _{CC} = MAX, See Note 2		6.9	13.8		6.9	13.8	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.

§ Not more than one output should be shorted at a time and the duration of the short circuit should not exceed one second.

NOTE 2: One input at 4.5 V, all others at GND.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{PLH}	A or B	Y	R _L = 667 Ω, C _L = 45 pF		12	24	ns
t _{PHL}					12	24	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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